

Description

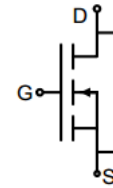
The XPXGT060N04D3RX uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge. It can be used in a wide variety of applications.

General Features

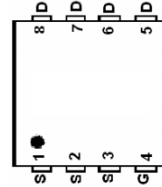
- V_{DS} 40V
- I_D (at $V_{GS} = 10V$) 60A
- $R_{DS(ON)}$ (at $V_{GS} = 10V$) < 6.5m Ω
- $R_{DS(ON)}$ (at $V_{GS} = 4.5V$) < 10.5m Ω
- 100% Avalanche Tested
- RoHS Compliant

Application

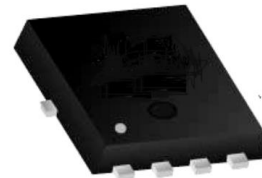
- Synchronous Rectification in SMPS or LED Driver
- UPS
- Motor Control
- BMS
- High Frequency Circuit



Schematic Diagram



Marking and pin assignment



DFN3X3-8L

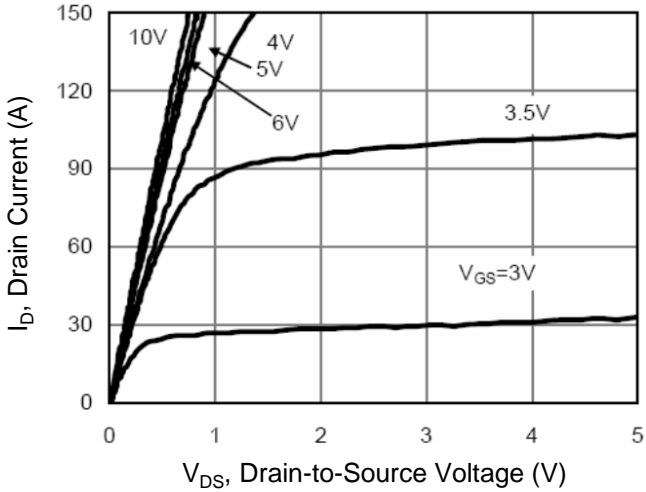
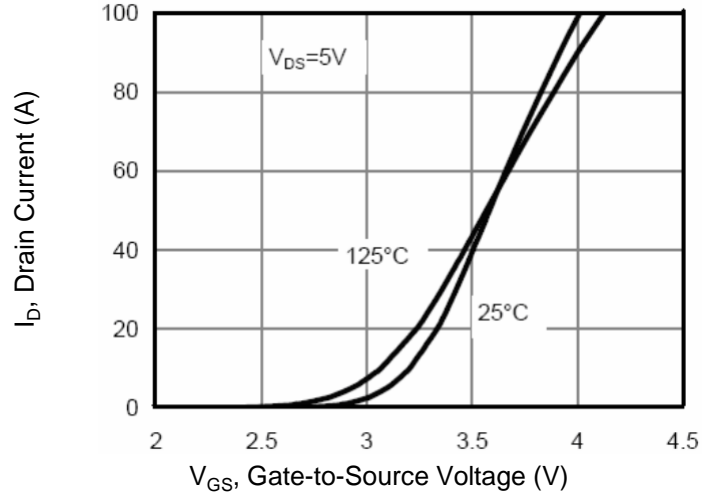
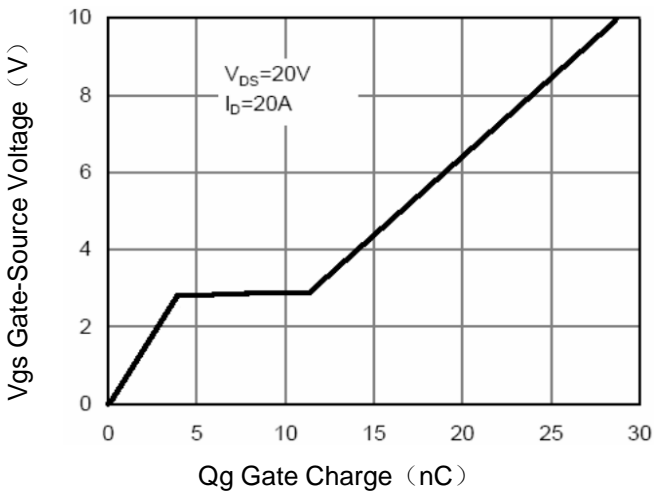
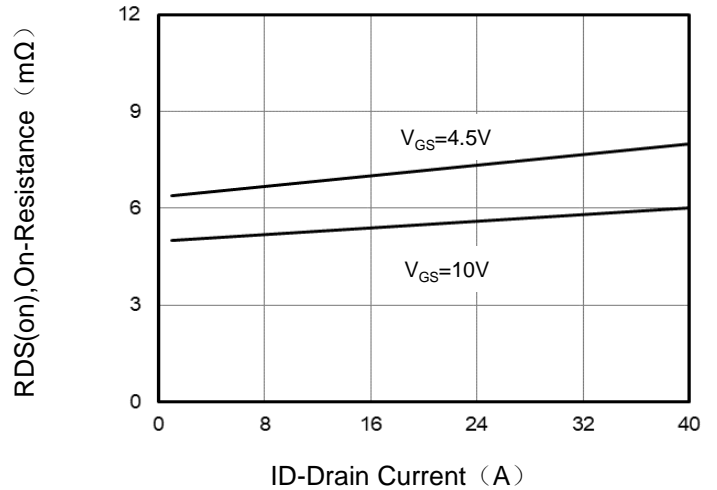
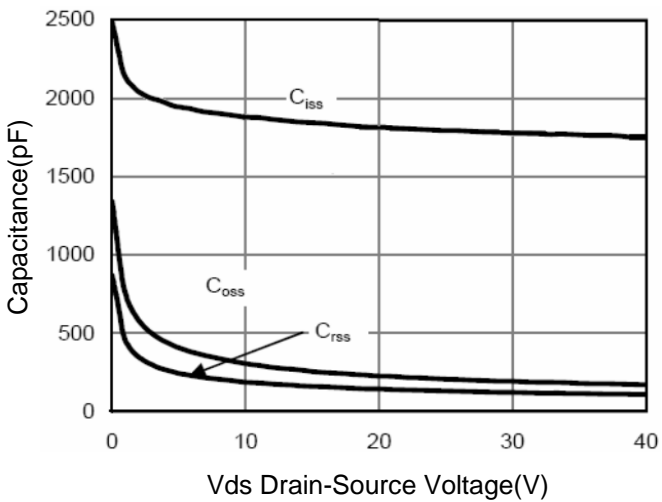
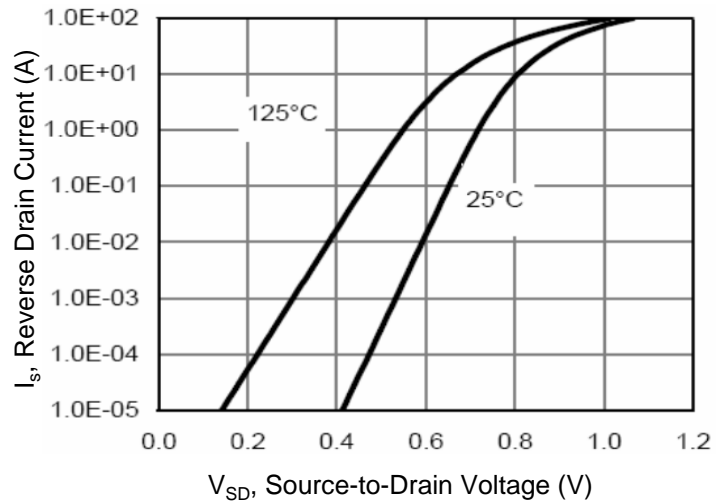
Device	Package	Marking	Packaging
XPXGT060N04D3RX	DFN3X3-8L	060N04	5000pcs/Reel

Absolute Maximum Ratings $T_C = 25^\circ\text{C}$, unless otherwise noted			
Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	40	V
Continuous Drain Current	I_D	60	A
Pulsed Drain Current (note1)	I_{DM}	160	A
Gate-Source Voltage	V_{GS}	± 20	V
Power Dissipation	P_D	36	W
Single pulse avalanche energy (note3)	E_{AS}	56	mJ
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 To 150	$^\circ\text{C}$
Thermal Resistance			
Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	R_{thJC}	3.8	$^\circ\text{C/W}$

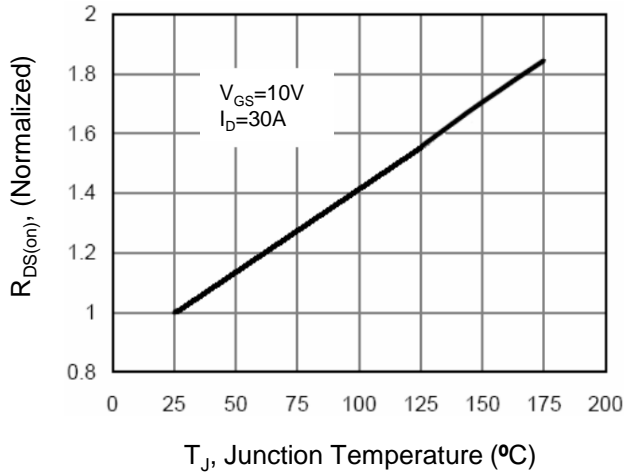
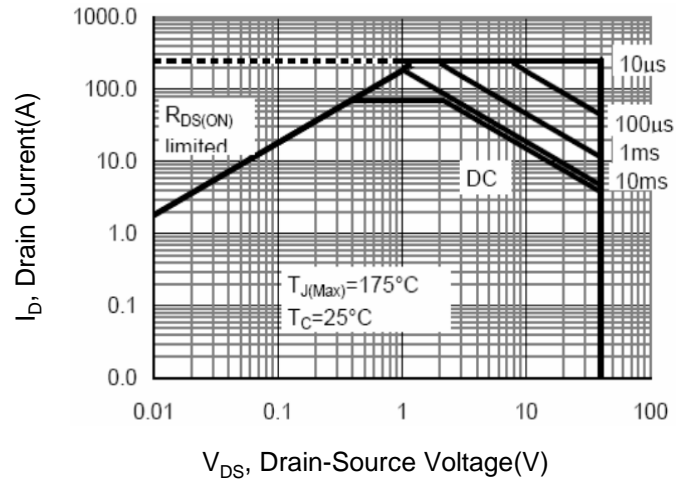
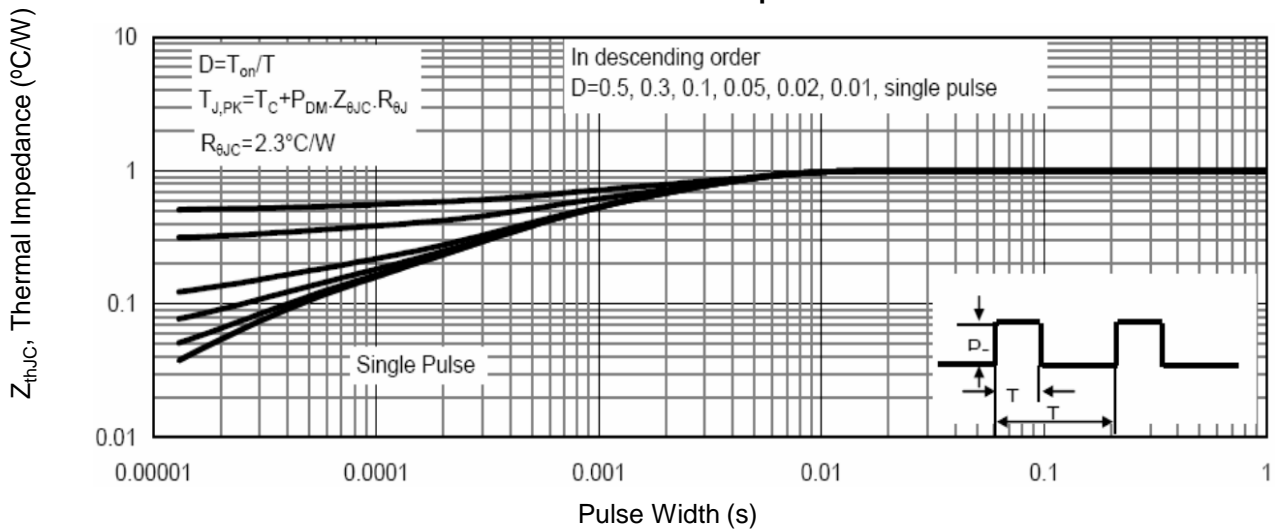
Specifications $T_J = 25^\circ\text{C}$, unless otherwise noted						
Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
Static Parameters						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	40	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 40V, V_{GS} = 0V$	--	--	1	μA
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20V$	--	--	± 100	nA
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.8	2.5	V
Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 30A$	--	5.5	6.5	m Ω
		$V_{GS} = 4.5V, I_D = 20A$	--	7.5	10.5	
Forward Transconductance	g_{FS}	$V_{DS}=5V, I_D=15A$	--	39	--	S
Dynamic Parameters						
Input Capacitance	C_{iss}	$V_{GS} = 0V,$ $V_{DS} = 20V,$ $f = 1.0\text{MHz}$	--	1269	--	pF
Output Capacitance	C_{oss}		--	60	--	
Reverse Transfer Capacitance	C_{rss}		--	20	--	
Total Gate Charge	Q_g	$V_{DS} = 20V,$ $I_D = 20A,$ $V_{GS} = 10V$	--	32	--	nC
Gate-Source Charge	Q_{gs}		--	7	--	
Gate-Drain Charge	Q_{gd}		--	3	--	
Turn-on Delay Time	$t_{d(on)}$	$V_{DD} = 20V,$ $I_D = 20A,$ $R_G = 1.6\Omega$	--	6.5	--	ns
Turn-on Rise Time	t_r		--	3	--	
Turn-off Delay Time	$t_{d(off)}$		--	21	--	
Turn-off Fall Time	t_f		--	3	--	
Drain-Source Body Diode Characteristics						
Continuous Body Diode Current	I_S	$T_C = 25^\circ\text{C}$	--	--	40	A
Body Diode Voltage	V_{SD}	$T_J = 25^\circ\text{C}, I_{SD} = 30A, V_{GS} = 0V$	--	--	1.2	V
Reverse Recovery Charge	Q_{rr}	$I_S = 20A, V_{GS} = 0V$ $di/dt=100A/\mu\text{s}$	--	16	--	nC
Reverse Recovery Time	t_{rr}		--	28	--	ns

Notes

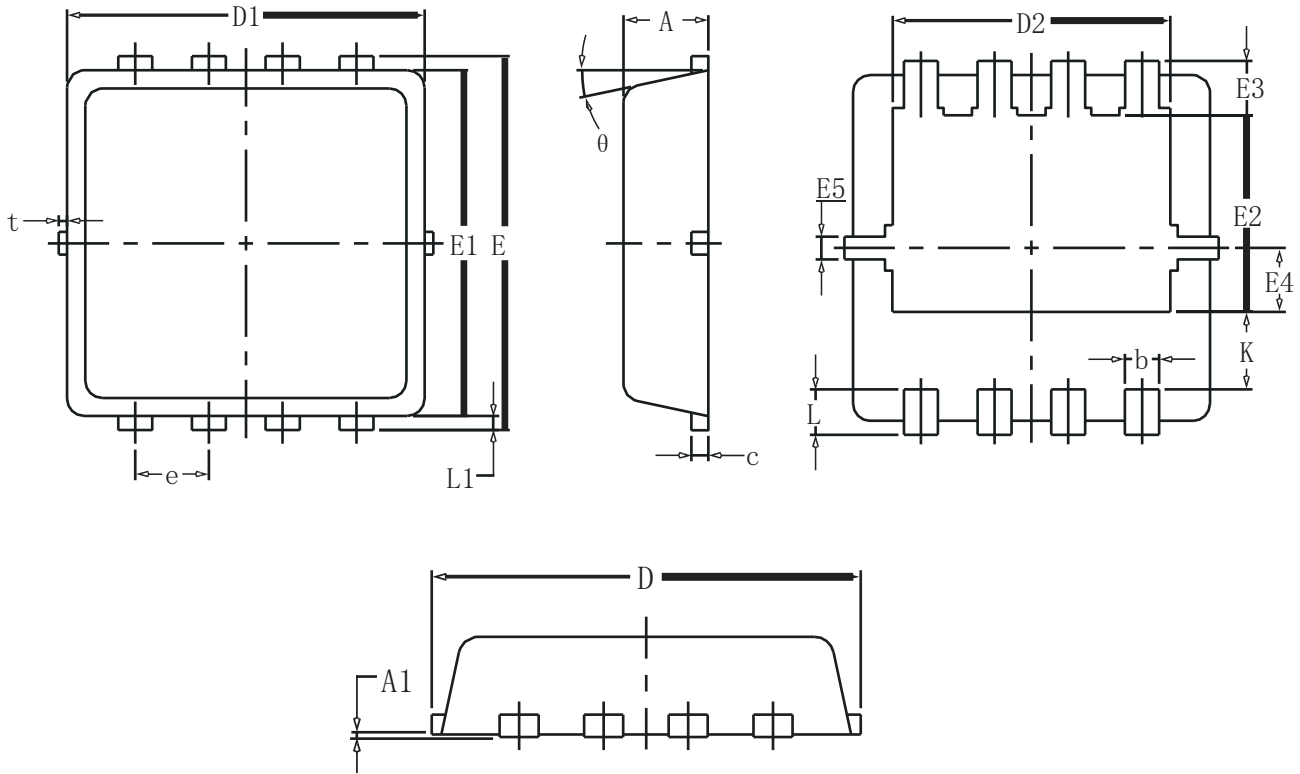
1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. Identical low side and high side switch with identical R_G
3. EAS condition : $T_J=25^\circ\text{C}$, $V_{DD}=40V, V_{GS}=10V, L=0.5\text{mH}, R_g=25\Omega$

Figure 1. Output Characteristics

Figure 2. Transfer Characteristics

Figure 3. Gate Charge

Figure 4. Drain Source On Resistance

Figure 5. Capacitance

Figure 6. Source-Drain Diode Forward


Typical Characteristics $T_J = 25^\circ\text{C}$, unless otherwise noted

Figure 7. Drain-Source On-Resistance

Figure 8. Safe Operation Area

Figure 9. Normalized Maximum Transient Thermal Impedance


DFN3X3-8L Package information



SYMBOL	COMMON		
	MM		
	MIN	NOM	MAX
A	0.70	0.75	0.85
A1	—	—	0.05
b	0.20	0.30	0.40
c	0.10	0.152	0.25
D	3.15	3.30	3.45
D1	3.00	3.15	3.25
D2	2.29	2.45	2.65
E	3.15	3.30	3.45
E1	2.90	3.05	3.20
E2	1.54	1.74	1.94
E3	0.28	0.48	0.65
E4	0.37	0.57	0.77
E5	0.10	0.20	0.30
e	0.60	0.65	0.70
K	0.59	0.69	0.89
L	0.30	0.40	0.50
L1	0.06	0.125	0.20
t	0	0.075	0.13
θ	10°	12°	14°

Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245°C ±5°C	5sec ±1 sec
Pb-Free device	260°C +0/-5°C	5sec ±1 sec



This integrated circuit can be damaged by ESD. UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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